

<b>Notice of References Cited</b>	Application/Control No. 10/720,526		Applicant(s)/Patent Under Reexamination LIN, JUNG KAN	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-2004/0089846	05-2004	Matsuno, Kenji	252/301.40S
	C	US-2004/0099875	05-2004	Lin, Jung Kan	257/100
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**NON-PATENT DOCUMENTS**

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